- 1 1. A method comprising:
- forming a wafer with a microelectromechanical
- 3 switch defined on a first face;
- forming a wafer with a film bulk acoustic
- 5 resonator on a first face; and
- 6 packaging said wafers in first face-to-first-face
- 7 alignment.
- 1 2. The method of claim 1 wherein packaging said
- 2 wafers in face-to-face alignment includes providing a
- 3 sealing material around the first faces of said wafers to
- 4 define a hermetically sealed chamber between said wafers.
- 1 3. The method of claim 2 including providing a third
- 2 wafer over a backside cavity in said wafer with a film bulk
- 3 acoustic resonator.
- 1 4. The method of claim 1 including providing a
- 2 conductive contact between an electrode on said film bulk
- 3 acoustic resonator and a contact on said
- 4 microelectromechanical switch.
- 1 5. The method of claim 1 including providing a
- 2 contact on the exterior of said packaged wafers through
- 3 said wafer with said film bulk acoustic resonator.

- 1 6. The method of claim 1 including providing a
- 2 contact on the exterior of said packaged wafers extending
- 3 through said wafer with said microelectromechanical switch.
- 1 7. The method of claim 1 including sawing through
- 2 said wafer with said film bulk acoustic resonator to make
- 3 contact with an electrode of said film bulk acoustic
- 4 resonantor.
- 1 8. The method of claim 7 including making a tapered
- 2 saw cut to remove a portion of said wafer with said film
- 3 bulk acoustic resonator.
- 1 9. The method of claim 8 including coating said
- 2 tapered surface with a conductor to form an exterior
- 3 contact on said packaged wafers.
- 1 10. The method of claim 1 further including combining
- 2 said wafer with a microelectromechanical switch and the
- 3 wafer with a film bulk acoustic resonator wherein at least
- 4 one of said wafers has a pre-applied sealing material.
- 1 11. The method of claim 1 including combining said
- 2 wafer with a microelectromechanical switch and said wafer
- 3 with a film bulk acoustic resonator with at least one of
- 4 said wafers having a pre-applied conductive material to

- 5 form an electrical connection between said wafers when
- 6 combined.

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- 1 12. A packaged electronic device comprising:
- 2 a microelectromechanical switch including a first
- 3 surface having a cantilevered switch element;
- 4 a film bulk acoustic resonator having a first
- 5 surface having upper and lower electrodes and a
- 6 piezoelectric film formed thereon;
- 7 said switch and said resonator arranged with said
- 8 first surfaces in opposition to one another; and
- 9 a sealing ring between said surfaces to define a
- 10 chamber between said switch and said resonator.
- 1 13. The device of claim 12 including electrical
- 2 contacts between said switch and said resonator extending
- 3 through said chamber.
- 1 14. The device of claim 12 wherein said resonator
- 2 includes a cavity in a second surface of said resonator,
- 3 said cavity being covered by a substrate.
- 1 15. The device of claim 12 including contacts
- 2 extending from the exterior of said device through said
- 3 resonator to contact at least one of said electrodes.

- 1 16. The device of claim 12 including contacts that
- 2 extend from the exterior of said device through said switch
- 3 to make electrical contact with said switch on its first
- 4 surface.
- 1 17. The device of claim 12 wherein said resonator has
- 2 tapered exterior conductive surfaces that make electrical
- 3 contact with said electrodes.
- 1 18. A semiconductor assembly comprising:
- a first wafer including a microelectromechanical
- 3 switch formed thereon on a first face of said first wafer;
- a second wafer with a film bulk acoustic
- 5 resonator formed on a first face of said second wafer; and
- 6 said wafers connected in first face-to-first face
- 7 alignment.
- 1 19. The assembly of claim 18 including a sealing
- 2 material around the first faces of said wafers to define a
- 3 hermetically sealed chamber between said wafers.
- 1 20. The assembly of claim 18 wherein said second
- 2 wafer includes a backside cavity and a third wafer formed
- 3 over said backside cavity.

- 1 21. The assembly of claim 18 including a conductive
- 2 contact extending between said film bulk acoustic resonator
- 3 and said microelectromechanical switch.
- 1 22. The assembly of claim 18 further including a
- 2 contact extending from the exterior of said assembly
- 3 through said wafer with said film bulk acoustic resonator
- 4 to make contact electrically with said film bulk acoustic
- 5 resonator.
- 1 23. The assembly of claim 18 including a contact on
- 2 the exterior of said assembly and extending through said
- 3 wafer with said microelectromechanical switch.
- 1 24. The assembly of claim 18 including a notch formed
- 2 in said film bulk acoustic resonator to enable electrical
- 3 connection from the outside world to said film bulk
- 4 acoustic resonator.